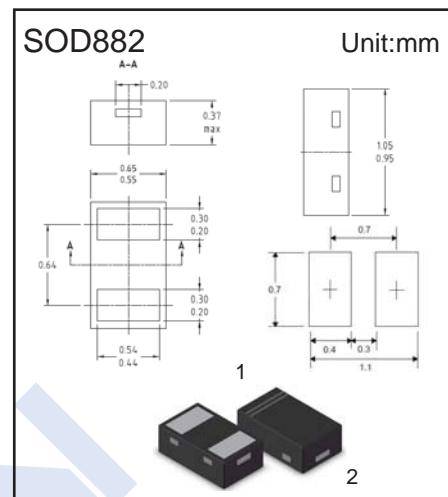


TVS Diodes

ESD8L5.0C

■ Features

- Transient protection for high-speed data lines
IEC 61000-4-2 (ESD) $\pm 15\text{kV}$ (Air)
 $\pm 8\text{kV}$ (Contact)
- IEC 61000-4-4 (EFT) 40A (5/50 ns)
- Protects one data, control or power line
- Low capacitance: 0.35pF
- Low leakage current: 10nA @ VRWM
- Low clamping voltage



■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Nominal Reverse Working Voltage	VRWM	5	V
ESD per IEC 61000-4-2 (Air)	VESD	± 17	KV
ESD per IEC 61000-4-2 (Contact)		± 12	
Junction Temperature	TJ	150	
Operating Temperature	TOPT	-55 to 125	°C
Storage Temperature range	Tstg	-55 to 150	

■ Electrical Characteristics Ta = 25°C

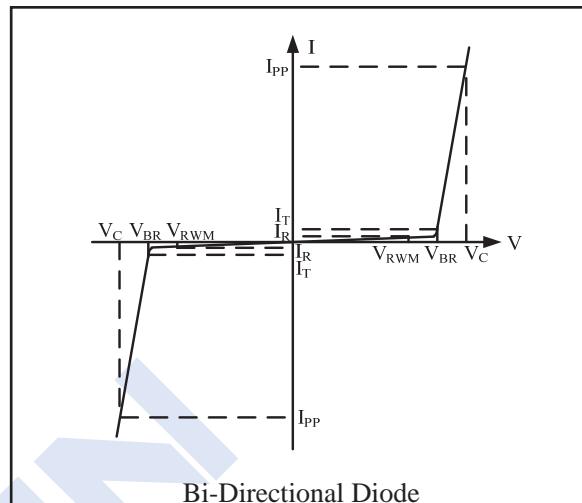
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Reverse breakdown voltage	VBR	I _T = 1 mA, Between I/O and I/O	6		11	V
Clamping Voltage	V _C	I _{PP} = 1A, t _p =8/20us Between I/O and I/O			12	
		I _{PP} = 2A, t _p =8/20us Between I/O and I/O			14	
Reverse voltage leakage current	I _R	VRWM= 5 V, Between I/O and I/O			1	uA
Parasitic Capacitance	C _{ESD}	VR= 0 V, f= 1 MHz, Between I/O and I/O			0.5	pF

TVS Diodes

ESD8L5.0C

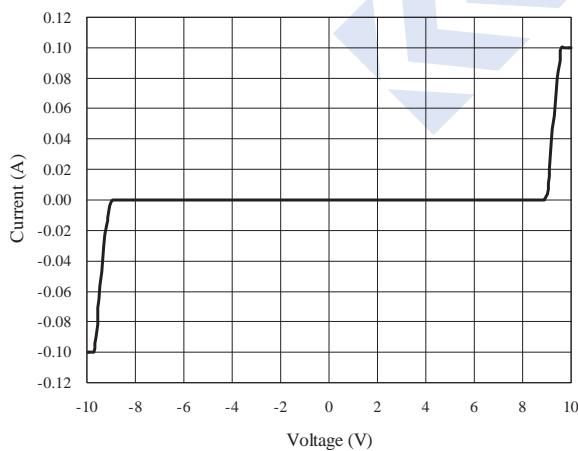
■ Electrical Characteristics ($T = 25^\circ C$)

Symbol	Parameter
V_{RWM}	Nominal Reverse Working Voltage
I_R	Reverse Leakage Current @ V_{RWM}
V_{BR}	Reverse Breakdown Voltage @ I_T
I_T	Test Current for Reverse Breakdown
V_C	Clamping Voltage @ I_{PP}
I_{PP}	Peak Pulse Current
C_{ESD}	Parasitic Capacitance
V_R	Reverse Voltage
f	Small Signal Frequency

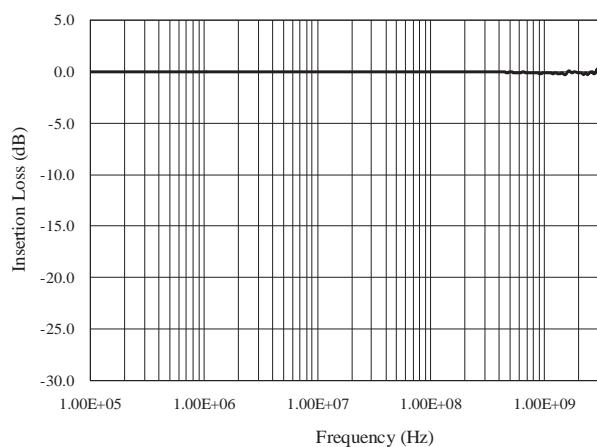


■ Typical Characteristics

Voltage Sweeping of I/O to I/O

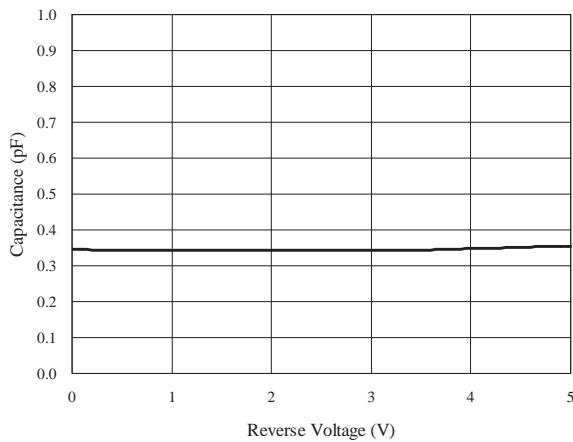


Insertion Loss S21 of I/O to I/O

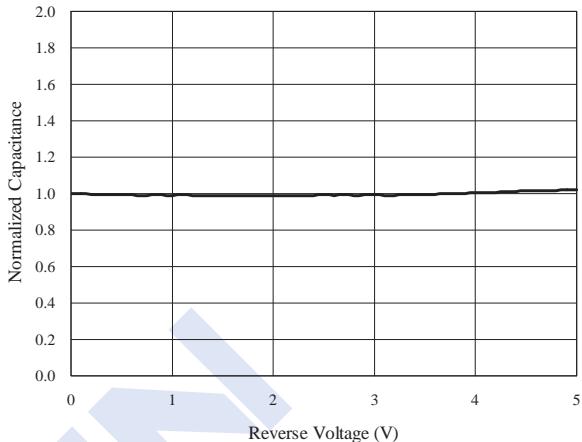
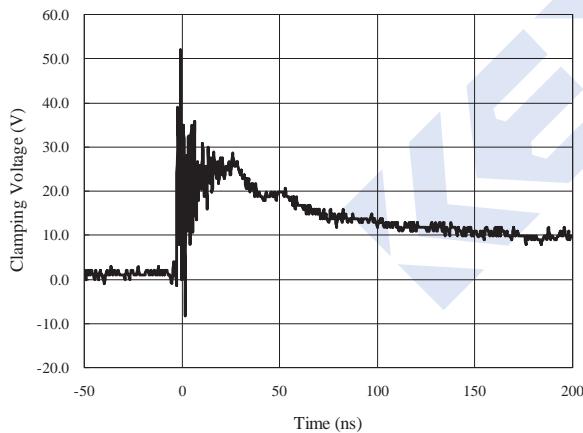
Capacitance vs. Voltage of I/O to I/O ($f = 1\text{MHz}$)

TVS Diodes**ESD8L5.0C****■ Typical Characteristics**

Capacitance vs. Reverse Voltage



Normalized Capacitance vs. Reverse Voltage

**ESD Clamping of I/O to I/O
(+8kV Contact per IEC 61000-4-2)****ESD Clamping of I/O to I/O
(-8kV Contact per IEC 61000-4-2)**